

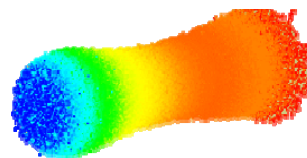
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## **Electron Emission Studies Using Enhanced QE Models**

**DESY-TEMF Collaboration Meeting  
S2/17 • R 114 • TEMF • Darmstadt  
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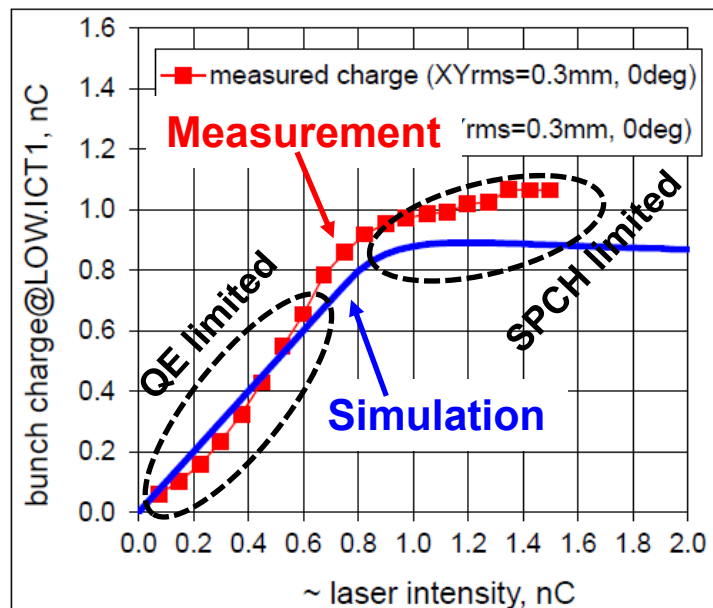
# Contents



- Motivation
- Beam dynamics codes
- Photocathode QE model(s)
- Dynamic charge production in QE limited regime
- Effects in space-charge dominated regime
- Summary and Outlook

# Motivation

1. **To understand measurement vs. simulation discrepancies for PITZ\***
  - Discrepancies in total bunch charge
2. **To improve beam dynamics codes for emission studies**
  - Conventional PIC/PP models: direct charge production not possible
  - Cathode phenomenon due to fields and driving laser pulses not modeled



**Charge vs. Laser Intensity**

**Introducing modified QE models (interfaces) to beam dynamics simulations**

\*M. Krasilnikov, Motivation of emission studies at PITZ, DESY, 06.2015



# Beam dynamics codes

## ❖ 3D Lienard-Wiechert (LW) PP code <sup>[1]</sup> → Implementation of QE models

- Exact LW field solution for relativistic charged particles
- No geometry (except for cathode)
- Numerically expensive (full particle history stored)

## ❖ Uniform Motion Average Frame (UMAF) PP code & ASTRA PIC code <sup>[2]</sup>

- Average rest beam frame (ASTRA / PARMELA type)
- No retardation or acceleration
- Numerically more efficient

## ❖ 3D CST Particle Studio (CST PS) PIC solver <sup>[3]</sup>

- Full-wave codes, full geometry
- Less efficient in 3D: not applicable for long accelerator structures

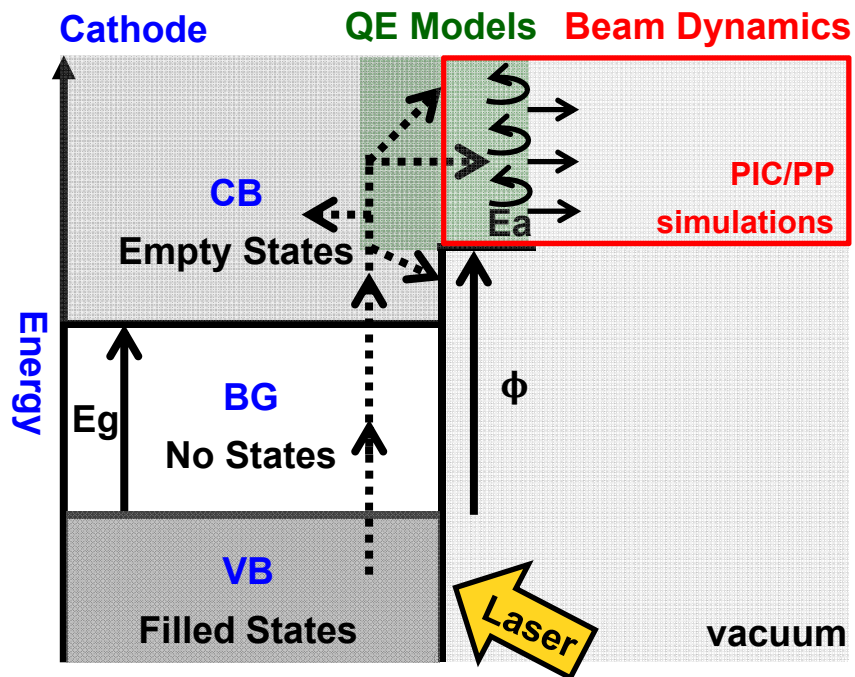
Demonstration  
of results

[1] E. Gjonaj, DESY/TEMF collaboration meeting, Hamburg, 2011.

[2] K. Floettmann, ASTRA particle tracking code [<http://www.desy.de/~mpyflo/>].

[3] Computer Simulation Technology, [www.cst.de](http://www.cst.de).

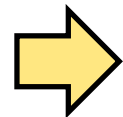
# Dynamic beam generation



Band structure sketch and QE interface  
between cathode and vacuum

- ❖ Cathode performance → Quantum Efficiency (QE)
- ❖ QE → work function  $\phi$  (energy)
- ❖ Modifications of  $\phi$ 
  - surface barrier reduction  $\Delta\phi_{sch}$  → field effect
  - plasma work function  $\Delta\phi_p$  → laser effect
- ❖ Cathode field,  $E_{cath}(r, t)$ 
  - **time and space dependent**
  - 3D full relativistic RF + space-charge fields
- ❖ Driving laser pulse,  $I(r, t)$ 
  - **time and space dependent**
  - beam halo and electron-hole plasma
- ❖ **Dynamic beam generation**

Theoretical QE forms



# (Semi-) Analytical QE models

## ❖ Based on Spicer's 3-step theory<sup>[4]</sup>

1. Photoexcitation
2. Transport to surface
3. Escape to vacuum

→ **simple formulas for QE**

## ❖ QE models

- **For metals:** Fowler-Du Bridge model<sup>[5]</sup>
- **For semiconductors:** Spicer's and Jensen's<sup>[4,6]</sup>

## ❖ Spicer's semiconductor model

Given laser intensity  $I(l, h\nu)$ ,  $l$ : penetration depth,

Photoemission current

$$i(h\nu)d(h\nu) = \int_0^l \alpha(h\nu) I(l, h\nu) P(l, h\nu) dl d(h\nu)$$

Absorption coefficient,  $\alpha(h\nu)$     Escape probability,  $P(l, h\nu)$



$$QE_{spicer} = \frac{B}{1 + g(h\nu - \phi)^{-m}}$$

$B$  → emission probability, form factor

$g$  → absorption factor

Exponent index,  $m = 1.5$  (experimental)

Material work function,  $\phi = E_g + E_a$

# (Semi-) Analytical QE models

## ❖ Kevin L. Jensen's semiconductor model [6]

$$QE = \underbrace{\frac{1}{2}(1 - R_w)}_{\text{absorption}} \left\{ \underbrace{\frac{8}{y^4} \int_1^y x^3 \left( \int_{\frac{1}{x}}^1 s f_\lambda(s, E_a x^2) ds \right) dx}_{\text{weighted scattering fraction}} \right\} \underbrace{\sqrt{1 + \frac{\Delta E}{E_a}}}_{\text{escape probability}}$$

For small  $\Delta E$  (near threshold), a simplified form:

$$QE_{Jensen} = \frac{1 - R_w}{2} \left[ \frac{1}{(p_0 + 1) \left(1 + \frac{E_a}{\Delta E}\right)^2} \right] \sqrt{1 + \frac{\Delta E}{E_a}}$$

$$\Delta E = h\nu - (E_g + E_a)$$

$E_g$ : band gap,  $E_a$ : electron affinity

$R_w$ : reflection factor

$p_0$ : form factor, ratio of penetration depth  
to distance between two events

For Cs<sub>2</sub>Te photocathodes

$$E_g = 3.3 \text{ eV}$$

$$E_a = 0.2 \text{ eV}$$

$$h\nu = 4.81 \text{ eV at } 257 \text{ nm}$$

# Model implementation

$$QE = \frac{B}{1 + g(h\nu - \phi)^{-1.5}} \text{ (Spicer's)}$$

$$QE = \frac{1}{2} (1 - R_w) \left[ \frac{1}{(p_0 + 1) \left(1 + \frac{E_a}{\Delta E}\right)^2} \right] \sqrt{1 + \frac{\Delta E}{E_a}} \text{ (Jensen's)}$$

$$QE = \eta(h\nu - \phi)^2 \text{ (Fowler-Dubridge model)}$$

## QE forms:

- 1> Power law different
- 2> Interpretation of modeling theory different

## Performances in charge production

→ see simulation results

## QE modifications

### - Modified cathode work function

$$\phi = E_g + E_a - \Delta\phi_{sch} + \Delta\phi_p$$

$$\Delta E = h\nu - \phi$$

### - Surface potential reduction (Schottky)

$$\Delta\phi_{sch}(r, t) = \sqrt{\frac{e^3}{4\pi\epsilon_0} E_{cath}(r, t)}$$

### - Relativistic full cathode field on-the-fly

$$E_{cath}(r, t) = E_{rf}(r, t) + E_{spch}(r, t)$$

### - Plasma work function (experimental)

$$\Delta\phi_p = \alpha * [I(r, t)]^{1/2}$$

$I$  → laser intensity,  $\alpha$  → material property constant [7]

### - Edge-halo in transverse laser profile [8]

$$W_l(r, R_c, \sigma) \sim \exp\left(\frac{R_c^2 - r^2}{2 * \sigma^2}\right)$$

### - Linear modification of initial energy ( $E_{p1}=4.05\text{eV}$ for Cs2Te)

$$E_{kin} = E_{p1} - \phi$$



# Model implementation

## ❖ Total bunch charge produced at the cathode

$$\Delta E = h\nu - \left( E_g + E_a - \sqrt{\frac{e^3}{4\pi\epsilon_0} [E_{rf}(r, t) + E_{spch}(r, t)] + \alpha(I(r, t))^{1/2}} \right)$$

$$QE(r, t) = \frac{1}{A \left(1 + \frac{E_a}{\Delta E}\right)^2} \sqrt{1 + \frac{\Delta E}{E_a}}$$

**QE varies with time and space**

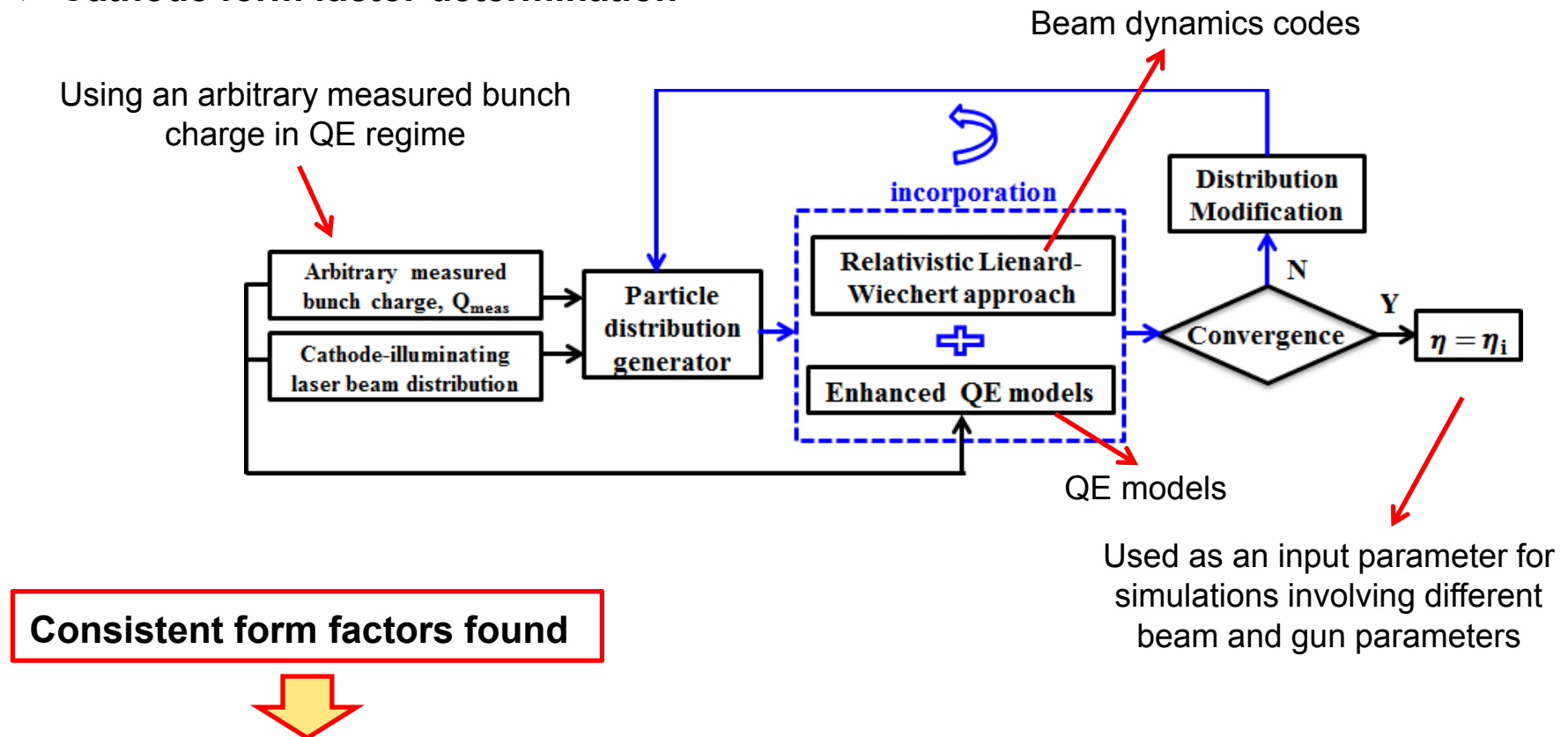
**↳ Cathode characterization needed**

$$Q(r, t) = \int_0^t \iint_S e \frac{P_{laser}(r, \tau) W_l(r, R_c, \sigma)}{h\nu} QE(r, \tau) d^2r d\tau$$

**Beam generation using full dynamic fields**

# Model implementation

## ❖ Cathode form factor determination





# Model implementation

## - cathode characterization for the PITZ gun<sup>[9,10]</sup>

No.	Laser Profile	RF Power	E <sub>laser</sub>	Form factor
1	GS	1.5 MW	8.22 nJ	0.0477
2			16.32 nJ	0.0456
3			24.79 nJ	0.0448
4			32.23 nJ	0.0432
1	GS	1.5 MW	34.96 nJ	0.002710
2			63.35 nJ	0.002608
3			113.34 nJ	0.002548
4			163.08 nJ	0.002451
5			205.81 nJ	0.002332
6			252.65 nJ	0.002371
1	GS	1.5 MW	8.22 nJ	9.0704
2			16.32 nJ	9.3736
3			24.79 nJ	9.5080
4			32.23 nJ	9.8863

Cathode 1 (QE≈8.5%)

$$\bar{\eta} \approx 0.0453$$

relative error < 6%

Cathode 2 (QE≈0.6%)

$$\bar{\eta} \approx 0.002503$$

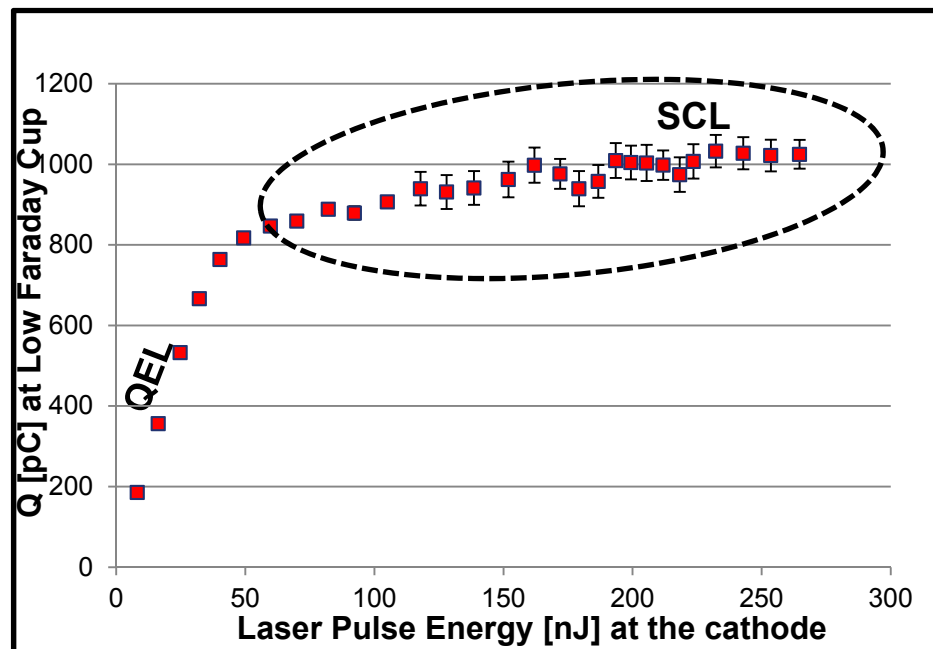
Cathode 1 (QE≈8.5%)

$$p_0 \approx 9.4596$$

Fowler-Dubridge model  
Jensen's model

1. Cathode form factors consistent for same cathode (models applicable)
2. Characterizations different for different QE models

# Simulations in SPCH dominated regime



## 1. Comparisons with measurements

- For a fresh cathode (QE= $\sim 8.5\%$ ) and a worn cathode (QE= $\sim 0.6\%$ )
- Experimental conditions:  
Prf=1.5MW, BSA=1.8mm, temporal profile: short Gaussian 1.5ps rms

## 2. Comparisons between enhanced QE models

- Fowler-Du Bridge model (metals)
- Spicer's model (semi)
- Jensen's model (semi)

## 3. Comparisons between numerical approaches

- UMAF PP
- LW PP
- CST PS PIC
- ASTRA PIC

# Simulations in SPCH dominated regime

## - comparisons between numerical approaches

- Using radial uniform distributions
- With or without Fowler-Dubridge model

### 4 vs. 5

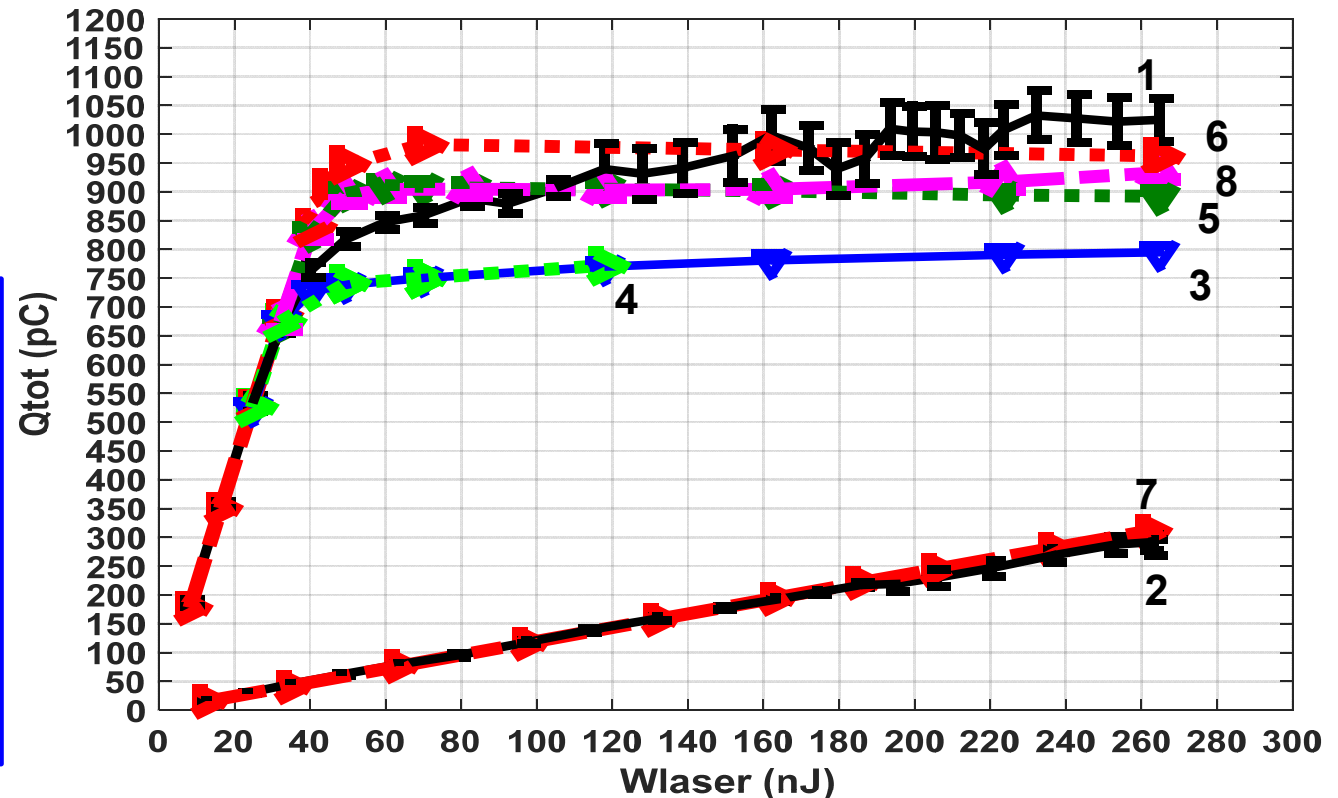
- both UMAF
- using QE model better, 5

### 5 vs. 6

- both using same QE
- full EM better, 6

### 6 vs. 8

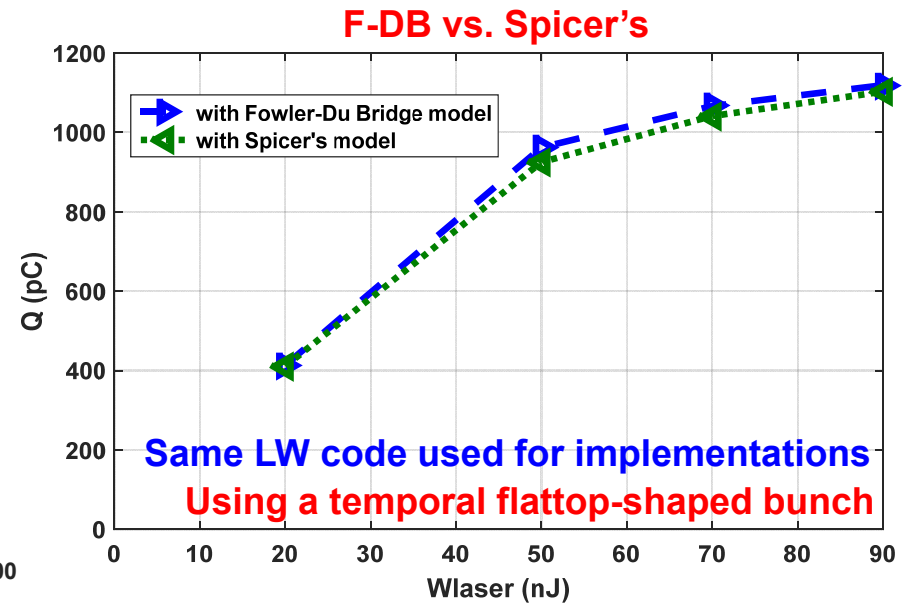
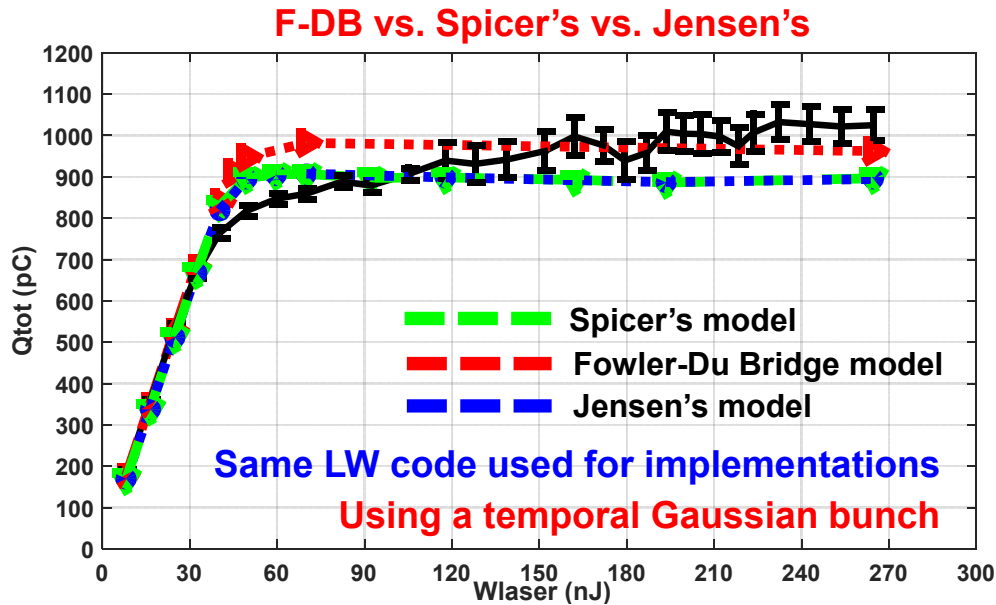
- both full EM
- using QE model better, 6



- |   |  |   |   |
|---|--|---|---|
| 1 | Measurements, "fresh" cathode, top curve   | 5 | UMAF PP simulations with F-DB model           |
| 2 | Measurements, "worn" cathode, bottom curve | 6 | LW simulations with F-DB model, fresh cathode |
| 3 | ASTRA simulations                          | 7 | LW simulations with F-DB model, worn cathode  |
| 4 | UMAF PP simulations                        | 8 | CST PS PIC simulations                        |

# Simulations in SPCH dominated regime

## - comparisons between enhanced QE models



### Spicer's vs. Jensen's

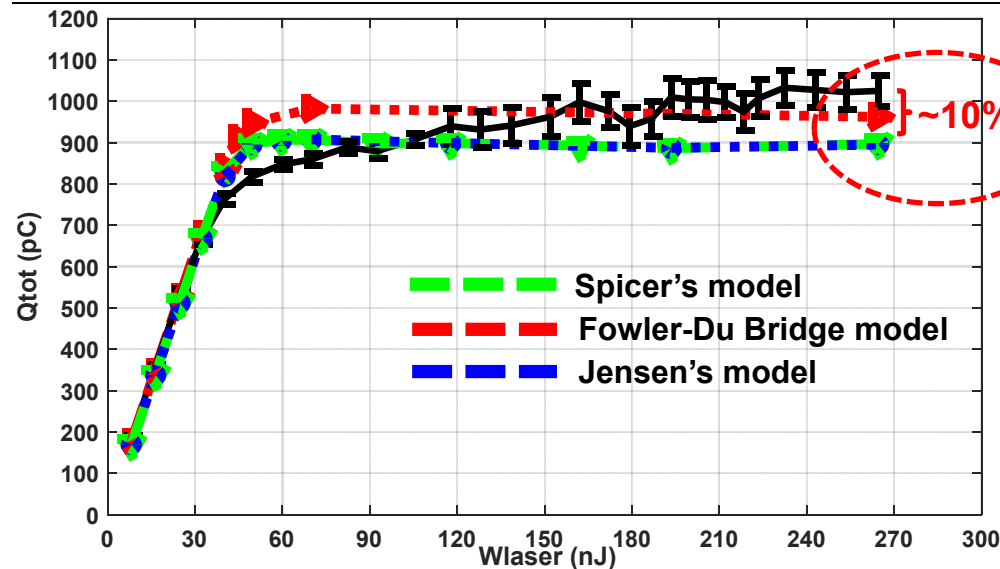
- both for semiconductors and threshold emission
- using same code for implementation
- good agreements, blue and green (left figure)

### F-DB vs. Spicer's

- Cathode characterizations different
- Using different form factors, measurements reproduced in QE regime
- In SPCH regime
  - F-DB gives slightly higher charges for GS bunches
  - Performances similar for FT bunches (right figure)

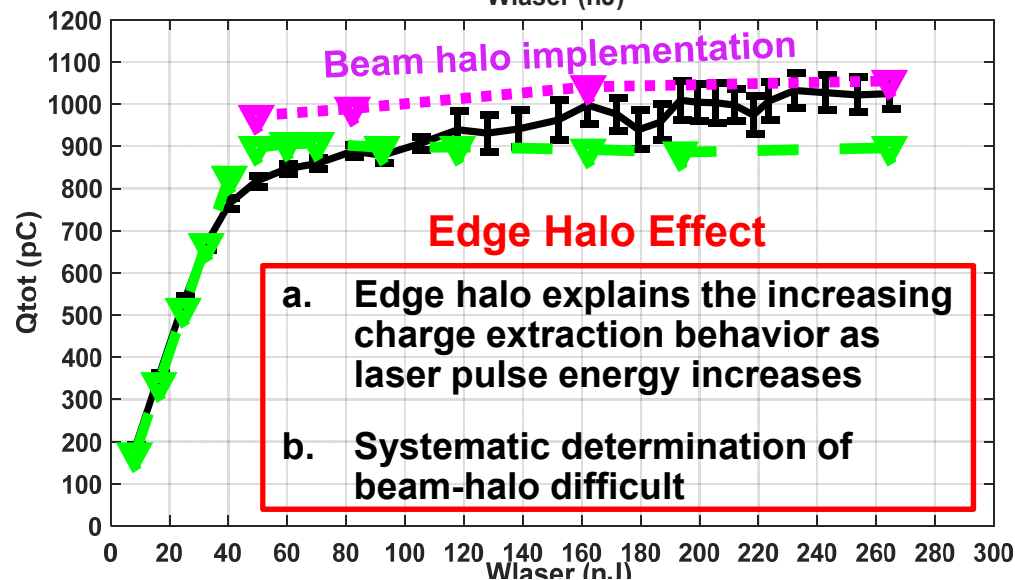
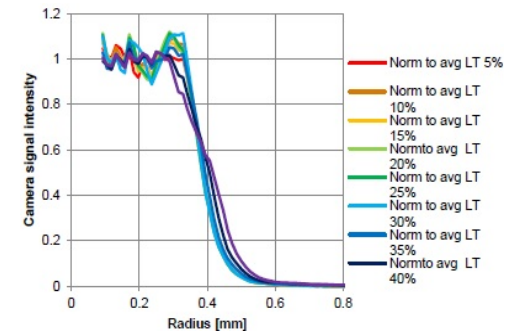
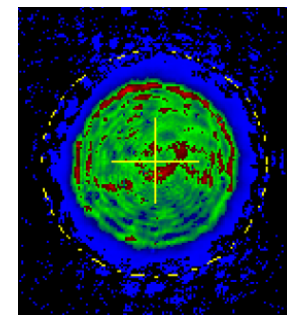
# Effects in SPCH dominated regime

-"edge halo effect"



❖ Slight increasing behavior in SPCH regime → induced edge halo in the transverse laser distribution

Laser spot on virtual cathode



❖ Beam-halo model of PITZ<sup>[8]</sup> used for implementation ( $R_c \sim 0.9$  mm,  $S_g \sim 0.25$ ) with LW approach and Spicer's model

# Effects in SPCH dominated regime

## -"plasma work function"

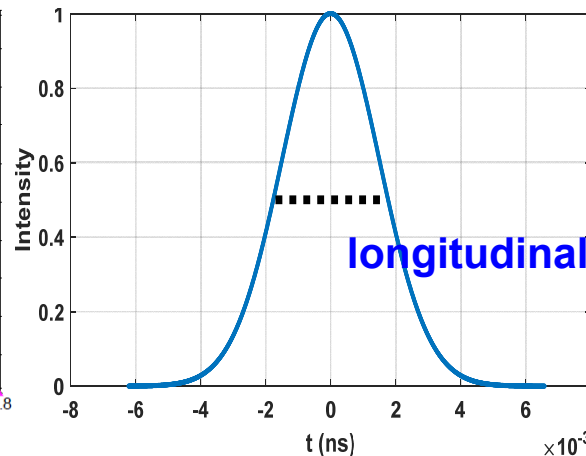
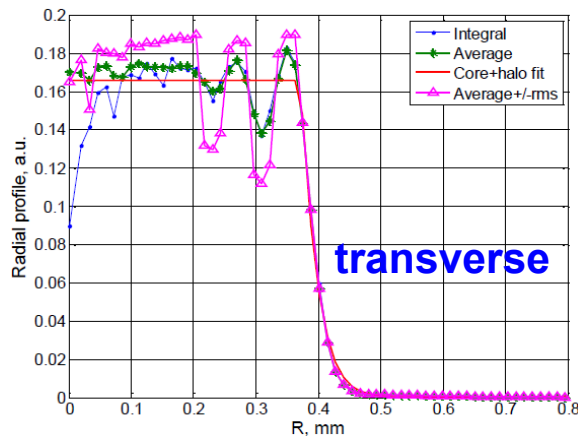
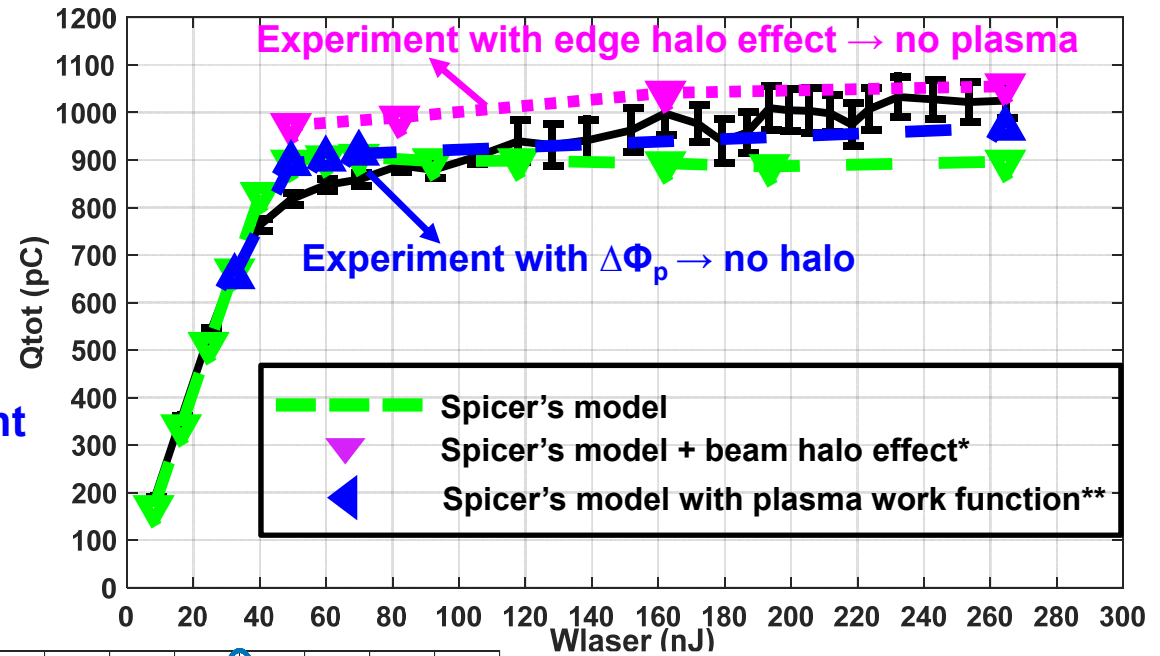
### ❖ Laser-induced plasma work function\*\*

a. Work function increased by high laser intensity induced plasma

b.  $\Delta\phi_p \sim \alpha * [I(r, t)]^{1/2}$

→ time and space dependent

I → laser intensity,  $\alpha$  → material property constant



\*M. Krasilnikov, Emission (re-measurements at PITZ, 2015

\*\*Max Zolotarev, SLAC-PUB-5896, 09.1992



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# Summary and Outlook

## 1. Incorporation of QE models with beam dynamics codes for emission modeling

## 2. Current status

- Simulation tool for emission studies
  - Multiple particle field computation approaches developed
  - Various emission models implemented
  - Relevant field and laser effects modeled
- Emission studies performed for PITZ using proposed method
  - QE models enhances emission
  - Full EM implementation enhances emission

## 3. Remaining problem

- Discrepancy in the transition area (Q w.r.t. laser energy)

## 4. Outlook and Discussion

- Edge-halo effect combined with plasma work function (?)
- More comparisons with measurements for validation

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# *Thank you for your attention!*



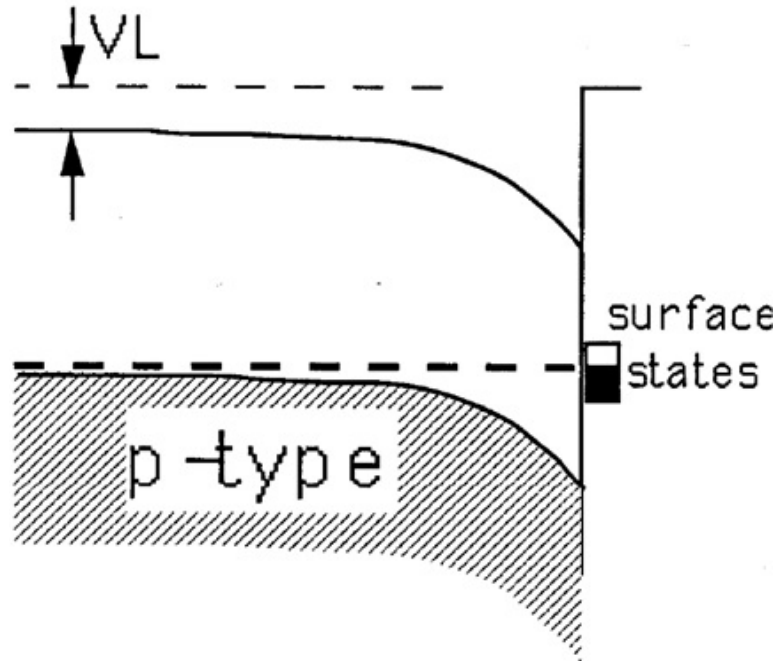
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## References

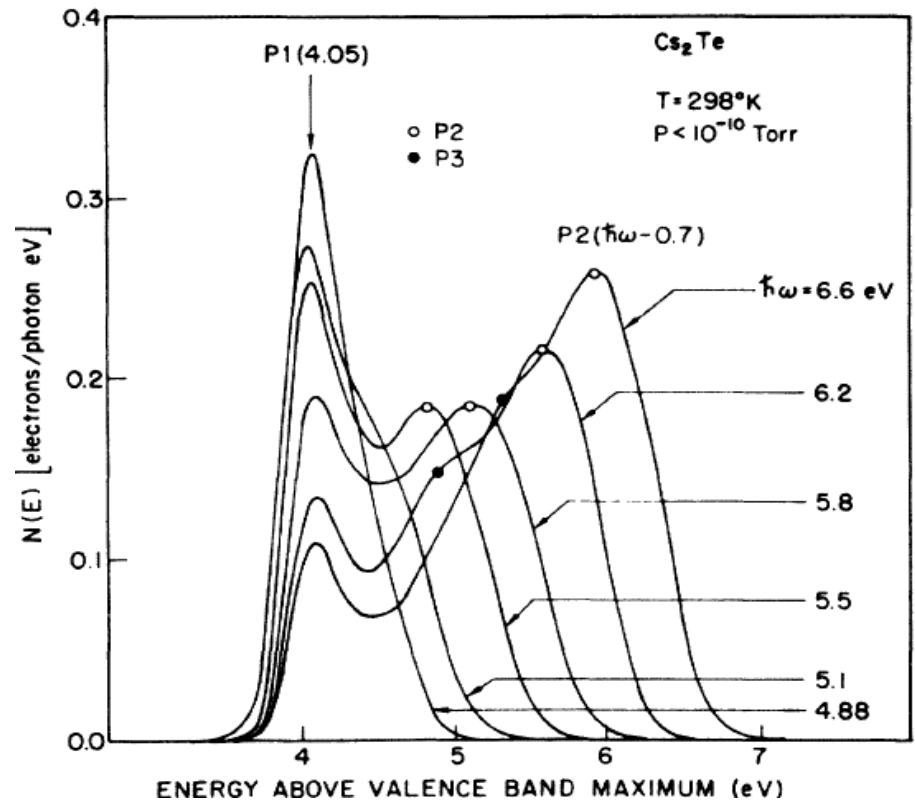
1. E. Gjonaj, DESY/TEMF collaboration meeting, Hamburg, 2011.
2. Computer Simulation Technology, [www.cst.de](http://www.cst.de).
3. K. Floettmann, ASTRA particle tracking code [www.desy.de](http://www.desy.de).
4. W.E. Spicer, Phys. Rev. 112, 114 (1958).
5. L.A. DuBridge, Phys. Rev. 43, 0727 (1933).
6. K.L. Jensen, J. Appl. Phys. 104, 044907 (2008).
7. Max Zolotorev, SLAC-PUB-5896, 09.1992.
8. M. Krasilnikov, Emission (re-) measurements at PITZ, 2015.
9. M. Krasilnikov, Phys. Rev. ST Accel. Beams 15, 100701 (2012).
10. F. Stephan, Phys. Rev. ST Accel. Beams 13, 020704 (2010).



# Backups



Band bending of p-type semiconductor



Final energy states of  $\text{Cs}_2\text{Te}$